


<b>Search Notes</b>  	<b>Application/Control No.</b>  10506644	<b>Applicant(s)/Patent Under Reexamination</b>  HOISCHEN ET AL.
	<b>Examiner</b>  Kortney L. Klinkel	<b>Art Unit</b>  1611

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Searched EAST and STN, see attached.	10/30/2008	KLK
Searched inventor names in PALM	10/30/2008	KLK
STIC searched compounds in STN, see results in SCORE	10/30/2008	KLK
Updated EAST search, see attached	8/17/2009	KLK
STIC searched structure in STN, see results in SCORE	8/17/2009	KLK
STIC searched structure in STN, see results in SCORE	2/2/2010	KLK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/K. L. K./  
Examiner, Art Unit 1611